

Gunshot Residue (GSD) analysis with SEM/RDX and applications of micro-XRF and XRD techniques for (automotive) paint analysis and future glass and document analysis

Tuesday, 29 May 2007 09:00 (1:00)

Content

Summary

Primary author(s) : B. NYS (National Institute for Criminalistics and Criminology, Brussels)

Presenter(s) : B. NYS (National Institute for Criminalistics and Criminology, Brussels)

Session Classification : Gunshot Residue (GSD) analysis with SEM/RDX and applications of micro-XRF and XRD techniques for (automotive) paint analysis and future glass and document analysis